

# Search Notes



Application/Control No.

10/669,527

Examiner

Stephen J. Cherry

Applicant(s)/Patent under Reexamination

FUJIKAWA ET AL.

Art Unit

2863

## SEARCHED

Class	Subclass	Date	Examiner
702	108 109 182 183 185 186		
717	124 126 131		
714	736		
update		3-20-06	SC

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
702	108, 109, 182, 183	and	
(software or program) with (test or decip)			
and (compare with pattern register). clm			
		3-20-06	SC

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Consult Wei Zhen AU 2191	6-20-05	S.C.
Consult M. Nghiem AU 2863	6-20-05	S.C.
See First Search	6-21-05	S.C.
Update Search	3-20-06	SC